

Abstract of the Disclosure:

A circuit configuration for measuring at least one operating parameter for an integrated circuit includes an analysis circuit connected to at least one external connection on the integrated circuit. The analysis circuit detects a plurality of voltage level changes on the external connection, which is used to control a method of operation for the integrated circuit, in particular, and supplies them to a counter circuit that logs at least one digitally coded value. The coded value is, then, output for analysis purposes to ascertain at least one operating parameter. This, advantageously, allows an average mode of operation for the integrated circuit to be logged during operation of the circuit in the application using parameters and allows respective operating states to be ascertained therefrom.

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